## Notice of References Cited Application/Control No. 10/645,699 Examiner Dennis Myint Applicant(s)/Patent Under Reexamination ENKO ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,256,675	07-2001	Rabinovich, Michael	709/241
*	В	US-6,026,414	02-2000	Anglin, Matthew Joseph	707/204
*	С	US-2003/0039148	02-2003	Riedle, Linda Ann	365/189.08
*	D	US-2004/0181605	09-2004	Nakatani et al.	709/233
*	E	US-5,544,347	08-1996	Yanai et al.	711/162
*	F	US-2002/0091746	07-2002	Umberger et al.	709/105
*	G	US-2002/0004890	01-2002	Ofek et al.	711/161
*	н	US-6,484,204	11-2002	Rabinovich, Michael	709/226
*	1	US-6,442,601	08-2002	Gampper et al.	709/218
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	<b>V</b>	
	W	
	x	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.